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| Search Notes  | Application/Control No. | Applicant(s)/Patent under Reexamination | |
| | 10/811,932 | YUE ET AL. | |
| | Examiner | Art Unit | |
| | Elias Desta | 2857 | |

| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | |
|---|------------|------|
| | DATE | EXMR |
| Method of search: EAST, YAHOO, GOOGLE, IEEE Explore, CRC and Semiconductor Publications | 5/17/2006 | E.D |
| Consulted: Patrick Assouad, cl. 702, au: 2857 (rest.), Nadine Norton, cl. 438, au: 1765; Anthony Knight, cl. 700, au. 2121. | 11/22/2005 | E.D |
| Text or key word searches: see attachment. | 5/17/2006 | E.D |
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| INTERFERENCE SEARCHED | | | |
|-----------------------|----------------|-----------|----------|
| Class | Subclass | Date | Examiner |
| 702 | 127,182 189 | 5/17/2006 | E.D |
| 438 | 5,10,17 | 5/17/2006 | E.D |
| 700 | 19,28,32 | 5/17/2006 | E.D |
| 219/490 | | 5/17/2006 | E.D |